


<b>Search Notes</b>  	<b>Application/Control No.</b>  10751327	<b>Applicant(s)/Patent Under Reexamination</b>  ZHANG ET AL.
	<b>Examiner</b>  Karen E Toth	<b>Art Unit</b>  3735

### SEARCHED

Class	Subclass	Date	Examiner
205	775, 777.5	2/28/2008	ket
600	309-367	2/28/2008	ket

### SEARCH NOTES

Search Notes	Date	Examiner
Searched EAST (USPAT, USPGPUB)	2/28/2008	ket
PALM inventor name search	2/28/2008	ket
class/subclass and keyword search	2/28/2008	ket
see attached		

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
all	calibrat\$3 and sensor and (data array curve) and (nominal initial original) and (adjust\$4 shift\$3) and (linear adj regression) and point	2/28/2008	ket